

PERRY JOHNSON LABORATORY ACCREDITATION, INC.

Certificate of Accreditation

Perry Johnson Laboratory Accreditation, Inc. has assessed the Laboratory of:

UMT Calibration Laboratory 5421 NW 74th Ave, Miami, FL 33166

(Hereinafter called the Organization) and hereby declares that Organization is accredited in accordance with the recognized International Standard:

ISO/IEC 17025:2017

This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (as outlined by the joint ISO-ILAC-IAF Communiqué dated April 2017):

Acoustic, Dimensional, Electrical, Mass, Force and Weighing Devices, Mechanical, Thermodynamic, Time and Frequency Calibration (As detailed in the supplement)

Accreditation claims for such testing and/or calibration services shall only be made from addresses referenced within this certificate. This Accreditation is granted subject to the system rules governing the Accreditation referred to above, and the Organization hereby covenants with the Accreditation body's duty to observe and comply with the said rules.

For PJLA:

Tracy Szerszen President

Perry Johnson Laboratory Accreditation, Inc. (PJLA) 755 W. Big Beaver, Suite 1325 Troy, Michigan 48084 Initial Accreditation Date: February 26, 2021 Issue Date:

April 10, 2023

Expiration Date: July 31, 2025

Accreditation No.: 112595

Certificate No.: L23-302

The validity of this certificate is maintained through ongoing assessments based on a continuous accreditation cycle. The validity of this certificate should be confirmed through the PJLA website: www.pjlabs.com



UMT Calibration Laboratory

5421 NW 74th Ave, Miami, FL 33166 Contact Name: Guillermo Blanco Phone: 1-800-222-5771

Accreditation is granted to the facility to perform the following calibrations:

Acoustic			
MEASURED INSTRUMENT,	RANGE OR NOMINAL	CALIBRATION AND	CALIBRATION
QUANTITY OR GAUGE	DEVICE SIZE AS	MEASUREMENT	EQUIPMENT
	APPROPRIATE	CAPABILITY EXPRESSED	AND REFERENCE
		AS AN UNCERTAINTY (±)	STANDARDS USED
Equipment to Measure	94 dB @ 1 kHz	0.27 dB	Acoustic Calibrator
Acoustic ^{FO}	114 dB @ 1 kHz		CM-1039

Dimensional

			CITY DE LETTON
MEASURED INSTRUMENT,	RANGE OR NOMINAL	CALIBRATION AND	CALIBRATION
QUANTITY OR GAUGE	DEVICE SIZE AS	MEASUREMENT	EQUIPMENT
	APPROPRIATE	CAPABILITY EXPRESSED	AND REFERENCE
		AS AN UNCERTAINTY (±)	STANDARDS USED
Outside Micrometer FO	Up to 20 in	$(5.4 + 7L) \mu in$	Gage Blocks
			Precision Sphere
			CM-1005
Inside Micrometer FO	Up to 20 in	$(100 + 7L) \mu in$	Gage Blocks
			CM-1005
Depth Micrometer FO	Up to 20 in	$(50 + 7L) \mu in$	Gage Blocks
			CM-1005
Dial/Digital Caliper FO	Up to 60 in	$(512 + 7L) \mu in$	Gage Blocks
			CM-1006
Dial/Digital Indicators FO	Up to 8 in	$(14.1 + 6L) \mu in$	Gage Blocks
			CM-1010
Crimp Tools ^{FO}	0.011 to 0.25 in	119 µin	Plug Gages
Wire Stripper FO			CM-1011
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Electrical

Electrical			
MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Equipment to Measure	Up to 300 mV	$60 \mu V/V + 3 \mu V$	Fluke 5500A
DC Voltage ^{FO}	330 mV to 3.3 V	50 μV/V + 5 μV	GIDEP
	3.3 V to 33 V	$50 \mu V/V + 50 \mu V$	
	33 V to 330 V	55 μV/V + 500 μV	
	330 V to 1 000 V	55 μV/V + 1 500 μV	
Equipment to Measure	Up to 3.3 mA	0.13 mA/A + 0.05 μA	
DC Current FO	3.3 mA to 33 mA	0.10 mA/A + 0.25 μA	
	33 mA to 330 mA	0.10 mA/A + 3.3 μA	
	330 mA to 2.2 A	0.30 mA/A + 44 μA	
	2.2 A to 11 A	0.6 mA/A + 330 μA	



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Equipment to Measure	Up to 11 Ω	$0.12 \text{ m}\Omega/\Omega + 8 \text{ m}\Omega$	Fluke 5500A
Resistance FO	11 Ω to 33 Ω	$0.12 \text{ m}\Omega/\Omega + 15 \text{ m}\Omega$	GIDEP
	33 Ω to 110 Ω	90 μΩ/Ω + 15 mΩ	
	110 Ω to 330 Ω	$90 \ \mu\Omega/\Omega + 15 \ m\Omega$	
	330 Ω to 1.1 k Ω	90 μΩ/Ω + 0.06 Ω	
	1.1 k Ω to 3.3 k Ω	90 μΩ/Ω + 0.06 Ω	
	3.3 k Ω to 11 k Ω	$90 \ \mu\Omega/\Omega + 0.6 \ \Omega$	
	11 kΩ to 33 kΩ	90 μΩ/Ω + 0.6 Ω	
	33 kΩ to 110 kΩ	$0.11 \text{ m}\Omega/\Omega + 6 \Omega$	
	110 k Ω to 330 k Ω	$0.12 \text{ m}\Omega/\Omega + 6 \Omega$	
	330 kΩ to 1.1 MΩ	$0.15 \text{ m}\Omega/\Omega + 55 \Omega$	
	1.1 MΩ to 3.3 MΩ	$0.15 \text{ m}\Omega/\Omega + 55 \Omega$	
	3.3 MΩ to 11 MΩ	$0.6 \text{ m}\Omega/\Omega + 550 \Omega$	
	11 MΩ to 33 MΩ	$1 \text{ m}\Omega/\Omega + 550 \Omega$	
	33 M Ω to 110 M Ω	$5 \text{ m}\Omega/\Omega + 5.5 \text{ k}\Omega$	
	110 MΩ to 330 MΩ	$5 \text{ m}\Omega/\Omega + 16.5 \text{ k}\Omega$	
Equipment to Measure	0.33 nF to 0.5 nF	5 mF/F + 0.01 nF	
Capacitance FO	0.5 nF to 1.1 nF	5 mF/F + 0.01 nF	
	1.1 nF to 3.3 nF	5 mF/F + 0.01 nF	
	3.3 nF to 11 nF	5 mF/F + 0.01 nF	
	11 nF to 33 nF	2.5 mF/F + 0.1 nF	
	33 nF to 110 nF	2.5 mF/F + 0.1 nF	
	110 nF to 330 nF	2.5 mF/F + 0.3 nF	
	0.33 μF to 1.1 μF	2.5 mF/F + 1 nF	
	1.1 μF to 3.3 μF	3.5 mF/F + 3 nF	
	3.3 µF to 11 µF	3.5 mF/F + 10 nF	
	11 µF to 33 µF	4 mF/F + 30 nF	
	33 μF to 110 μF	5 mF/F + 100 nF	
	110 µF to 330 µF	7 mF/F + 300 nF	
	330 µF to 1.1 mF	1 mF/F + 300 nF	



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	Valtaas	AS AN UNCERTAINTY (±)	STANDARDS USED
Equipment to Measure AC (At the listed frequencies) FC			Fluke 5500A GIDEP
10 Hz to 45 Hz	1 mV to 33 mV	1.5 mV/V + 90 μV	
45 Hz to 10 kHz	1 mV to 33 mV	0.4 mV/V + 90 μV	-
10 kHz to 20 kHz	1 mV to 33 mV	0.6 mV/V + 90 μV	_
20 kHz to 50 kHz	1 mV to 33 mV	1.5 mV/V + 90 μV	-
50 kHz to 100 kHz	1 mV to 33 mV	2.5 mV/V + 90 μV	-
100 kHz to 500 kHz	1 mV to 33 mV	3 mV/V + 90 μV	_
Equipment to Measure AC (At the listed frequencies)			
10 Hz to 45 Hz	33 mV to 330 mV	1.5 mV/V + 90 μV	
45 Hz to 10 kHz	33 mV to 330 mV	0.4 mV/V + 90 μV	
10 kHz to 20 kHz	33 mV to 330 mV	0.6 mV/V + 90 μV	
20 kHz to 50 KHz	33 mV to 330 mV	1.5 mV/V + 90 μV	
50 kHz to 100 KHz	33 mV to 330 mV	$2 \text{ mV/V} + 90 \mu \text{V}$	
100 kHz to 500 KHz	33 mV to 330 mV	$2 \text{ mV/V} + 90 \mu \text{V}$	
Equipment to Measure AC (At the listed frequencies) FO			
45 Hz to 10 kHz	0.33 V to 3.3 V	$0.4 \text{ mV/V} + 90 \mu \text{V}$	
10 kHz to 20 kHz	0.33 V to 3.3 V	$0.6 \text{ mV/V} + 90 \mu \text{V}$	
Equipment to Measure AC (At the listed frequencies) F)		
45 Hz to 10 kHz	3.3 V to 33 V	0.35 mV/V + 2 mV	
10 kHz to 20 kHz	3.3 V to 33 V	0.8 mV/V + 2 mV	
Equipment to Measure AC (At the listed frequencies) FC)	_	
45 Hz to 1 kHz	33 V to 329.999 V	1.5 mV/V + 10 mV	
Equipment to Measure AC (At the listed frequencies) FO			
45 Hz to 1 kHz	330 V to 1 000 V	1.5 mV/V + 30 mV	
1 kHz to 10 kHz	330 V to 1 000 V	0.7 mV/V + 30 mV	



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Electrical		1	1
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Equipment to measure AC			Fluke 5500A
(At the listed frequencies) ^{Fe}			GIDEP
10 Hz to 20 Hz	0.03 mA to 0.33 mA	2.5 mA/A + 0.15 μA	-
20 Hz to 45 Hz	0.03 mA to 0.33 mA	1.25 mA/A + 0.15 μA	
45 Hz to 1 kHz	0.03 mA to 0.33 mA	1.25 mA/A + 0.25 μA	
1 kHz to 5 kHz	0.03 mA to 0.33 mA	4 mA/A + 0.15 μA	
5 kHz to 10 kHz	0.03 mA to 0.33 mA	12.5 mA/A + 0.15 μA	
Equipment to measure AC ((At the listed frequencies) ^{F(C)}		•	
10 Hz to 20 Hz	0.33 mA to 3.3 mA	2 mA/A + 0.3 µA	
20 Hz to 45 Hz	0.33 mA to 3.3 mA	1 mA/A + 0.3 μA	
45 Hz to 1 kHz	0.33 mA to 3.3 mA	1 mA/A + 0.3 μA	
1 kHz to 5 kHz	0.33 mA to 3.3 mA	2 mA/A + 0.3 µA	
5 kHz to 10 kHz	0.33 mA to 3.3 mA	6 mA/A + 0.3 μA	-
Equipment to measure AC ((At the listed frequencies) ^{FG}			
10 Hz to 20 Hz	33 mA to 330 mA	2 mA/A + 30 µA	
20 Hz to 45 Hz	33 mA to 330 mA	1 mA/A + 30 μA	
45 Hz to 1 kHz	33 mA to 330 mA	0.9 mA/A + 30 μA	
1 kHz to 5 kHz	33 mA to 330 mA	2 mA/A + 30 µA	
5 kHz to 10 kHz	33 mA to 330 mA	6 mA/A + 30 μA	
Equipment to measure AC (At the listed frequencies)			
10 Hz to 45 Hz	0.33 mA to 2.2 A	2 mA/A + 300 µA	
45 Hz to 1 kHz	0.33 mA to 2.2 A	1 mA/A + 300 µA	k
1 kHz to 5 kHz	0.33 mA to 2.2 A	7.5 mA/A + 300 μA]
Equipment to measure AC (At the listed frequencies) ^{F(C)}			
45 Hz to 65 Hz	2.2 A to 11 A	0.6 mA/A + 2 000 μA	
65 Hz to 500 Hz	2.2 A to 11 A	1 mA/A + 2 000 μA	
500 Hz to 1 kHz	2.2 A to 11 A	3.3 mA/A + 2 000 μA	1



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Temperature Calibration,	-210 ° C to 1 200 ° C	0.6 ° C	Electrical Simulation of
Indication, and Control Equipment used with	-200 ° C to 1 375 ° C	0.7 ° C	Thermocouple Output Fluke 5500A
Thermocouple Type E ^{FO}	-250 ° C to 400 ° C	0.8 ° C	GIDEP
1 71	-250 ° C to 1 000 ° C	0.9 ° C	
Temperature Calibration,	-210 ° C to 1 200 ° C	0.6 ° C	
Indication, and Control Equipment used with	-200 ° C to 1 375 ° C	0.7 ° C	
Thermocouple Type J ^{FO}	-250 ° C to 400 ° C	0.8 ° C	
J J J J J J	-250 ° C to 1 000 ° C	0.9 ° C	
Temperature Calibration,	-210 ° C to 1 200 ° C	0.6 ° C	
Indication, and Control Equipment used with	-200 ° C to 1 375 ° C	0.7 ° C	
Thermocouple Type K ^{FO}	-250 ° C to 400 ° C	0.8 ° C	
	-250 ° C to 1 000 ° C	0.9 ° C	
Temperature Calibration,	-210 ° C to 1 200 ° C	0.6 ° C	
Indication, and Control Equipment used with	-200 ° C to 1 375 ° C	0.7 ° C	
Thermocouple Type T ^{FO}	-250 ° C to 400 ° C	0.8 ° C	
J J J J J	-250 ° C to 1 000 ° C	0.9 ° C	
Temperature Calibration,	-200 ° C to -80 ° C	0.1 ° C	Electrical Simulation of
Indication and Control Equipment Used With	-80 ° C to 0 ° C	0.1 ° C	RTD Output Fluke 5500A
RTD Pt 385 100Ω FO	Up to 100 ° C	0.14 ° C	GIDEP
	100 ° C to 300 ° C	0.18 ° C	
	300 ° C to 400 ° C	0.2 ° C	
	400 ° C to 630 ° C	0.24 ° C	
	630 ° C to 800 ° C	0.46 ° C	
Temperature Calibration,	-200 °C to -190 °C	0.5 °C	
Indication and Control	-190 °C to -80 °C	0.08 °C	
Equipment Used With RTD Pt 3916 $100\Omega^{FO}$	-80 °C to 0 °C	0.1 °C	
	Up to 100 °C	0.12 °C	
	100 °C to 260 °C	0.14 °C	
	260 °C to 300 °C	0.16 °C	
	300 °C to 400 °C	0.18 °C	
	400 °C to 600 °C	0.2 °C	
	600 °C to 630 °C	0.46 °C	



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Temperature Calibration,	-200 ° C to -80 ° C	0.08 ° C	Electrical Simulation of
Indication and Control Equipment Used With	-80 ° C to 0 ° C	0.08 ° C	RTD Output Fluke 5500A
RTD Pt 385 200Ω FO	Up to 100 ° C	0.08 ° C	GIDEP
	100 ° C to 260 ° C	0.1 ° C	
	260 ° C to 300 ° C	0.24 ° C	
	300 ° C to 400 ° C	0.26 ° C	
	400 ° C to 600 ° C	0.28 ° C	
	600 ° C to 630 ° C	0.32 ° C	
Temperature Calibration,	-200 ° C to -80 ° C	0.1 ° C	
Indication and Control	-80 ° C to 0 ° C	0.06 ° C	
Equipment Used With RTD Pt 385 1000Ω ^{FO}	Up to 100 ° C	0.06 ° C	
KID 11 505 100022	100 ° C to 300 ° C	0.08 ° C	
	100 ° C to 260 ° C	0.2 ° C	-
	260 ° C to 300 ° C	0.12 ° C	•
	300 ° C to 400 ° C	0.14 ° C	
	400 ° C to 600 ° C	0.14 ° C	
	600 ° C to 630 ° C	0.46 ° C	
Temperature Calibration,	-80 ° C to 0 ° C	0.16 ° C	
Indication and Control	Up to 100 ° C	0.16 ° C	•
Equipment Used With RTD PtNi 385 $120\Omega^{FO}$	100 ° C to 260 ° C	0.28 ° C	•
Temperature Calibration, Indication and Control Equipment Used With RTD Cu 427, 10Ω ^{FO}	-10 ° C to 260 ° C	0.6 ° C	
Equipment to Output DC C	urrent Clamp Meters FO		Fluke 5500A
10 Turn Coil	3.2 A to 32 A	0.6 mA/A + 1.18 mA	Fluke 9100-200
	32 A to 105 A	0.55 mA/A + 9.4 mA	GIDEP
	105 A to 200 A	0.55 mA/A + 45 mA	
50 Turn Coil	16 A to 160 A	0.6 mA/A + 5.9 mA	
	160 A to 525 A	0.055 mA/A + 47 mA	
	525 A to 1 000 A	0.055 mA/A + 225 mA	



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Equipment to Output DC	10 nV to 100 mV	$10 \mu V/V + 0.52 \mu V$	Keysight 3458A
Voltage ^{FO}	100 mV to 1 V	9.3 μV/V + 1.0 μV	GIDEP
	1 V to 10 V	9.3 μV/V + 7.1 μV	
	10 V to 100 V	12 μV/V + 83 μV	
	100 V to 1 000 V	$12 \mu V/V + 0.90 mV$	
Equipment to Output	10 μΩ to 10 Ω	17 μΩ/Ω + 53 μΩ	
Resistance FO	10 Ω to 100 Ω	14 μΩ/Ω + 0.63 mΩ	
	100 Ω to 1 k Ω	$12 \mu\Omega/\Omega + 3.7 m\Omega$	
	1 kΩ to 10 kΩ	$12 \mu\Omega/\Omega + 30 \mathrm{m}\Omega$	
	10 kΩ to 100 kΩ	12 μΩ/Ω + 0.24 Ω	
	100 k Ω to 1 M Ω	$17 \mu \Omega / \Omega + 3.7 \Omega$	
	1 M Ω to 10 M Ω	58 μΩ/Ω + 0.18 kΩ	
	10 MΩ to 100 MΩ	$0.58 \text{ m}\Omega/\Omega + 1.2 \text{ k}\Omega$	
	100 M Ω to 1 G Ω	$5.8 \text{ m}\Omega/\Omega + 13 \text{ k}\Omega$	
Equipment to Output DC	10 µA to 100 µA	23 µA/A + 1.2 nA	
Current ^{FO}	100 µA to 1 mA	23 µA/A + 8.1 nA	
	1 mA to 10 mA	23 µA/A + 80 nA	
	10 mA to 100 mA	41 μΑ/Α + 1.4 μΑ	
	100 mA to 1 A	0.13 mA/A + 12 μA	
	1 A to 3 A	0.14 % of rdg + 0.73 mA	Agilent 34401A GIDEP
	3 A to 6 A	1.2 % of rdg + 4.1 mA	Fluke 179
	6 A to 10 A	1.2 % of rdg + 35.9 mA	GIDEP
Equipment to Output AC V (At the listed frequencies)	Keysight 3458A GIDEP		
1 Hz to 40 Hz	10 nV to 10 mV	0.03% of rdg + 4.3μ V	
40 Hz to 1 kHz	10 nV to 10 mV	0.02% of rdg + 2.9 μ V	
1 kHz to 20 kHz	10 nV to 10 mV	0.03% of rdg + 2.9 μ V	
20 kHz to 50 kHz	10 nV to 10 mV	0.12% of rdg + 2.9 μ V	
100 kHz to 300 kHz	10 nV to 10 mV	4.6 % of rdg + 3.5 μV	



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Equipment to Output AC V	oltage ^{FO}		Keysight 3458A
(At the listed frequencies)	10 N/ 100 N		GIDEP
1 Hz to 40 Hz	10 mV to 100 mV	$0.01 \% \text{ of } rdg + 13 \mu V$	-
40 Hz to 1 kHz	10 mV to 100 mV	0.01 % of rdg + 12 µV	
1 kHz to 20 kHz	10 mV to 100 mV	0.02 % of rdg + 12 μV	
20 kHz to 50 kHz	10 mV to 100 mV	0.03 % of rdg + 12 μV	
50 kHz to 100 kHz	10 mV to 100 mV	0.09 % of rdg + 12 μ V	
100 kHz to 300 kHz	10 mV to 100 mV	0.35 % of rdg + 17 μ V	
300 kHz to 1 MHz	10 mV to 100 mV	1.2 % of rdg + 17 μV	
1 MHz to 2 MHz	10 mV to 100 mV	1.7 % of rdg + 17 μV	
Equipment to Output AC V (At the listed frequencies)			
1 Hz to 40 Hz	100 mV to 1 V	0.01 % of rdg + 65 μ V	
40 Hz to 1 kHz	100 mV to 1 V	0.01 % of rdg + 52 μV	
1 kHz to 20 kHz	100 mV to 1 V	$0.02 \% \text{ of } rdg + 52 \mu V$	
20 kHz to 50 kHz	100 mV to 1 V	0.03% of rdg + 52 μ V	
50 kHz to 100 kHz	100 mV to 1 V	0.09 % of rdg + 52 μ V	
100 kHz to 300 kHz	100 mV to 1 V	0.35 % of rdg + 0.12 mV	
300 kHz to 1 MHz	100 mV to 1 V	1.2 % of rdg + 0.12 mV	
1 MHz to 2 MHz	100 mV to 1 V	1.7 % of rdg + 0.12 mV	
Equipment to Output AC V (At the listed frequencies)	oltage ^{FO}		
1 Hz to 40 Hz	1 V to 10 V	0.01 % of rdg + 0.46 mV	
40 Hz to 1 kHz	1 V to 10 V	0.01 % of rdg + 0.23 mV	
1 kHz to 20 kHz	1 V to 10 V	0.02 % of rdg + 0.23 mV	n.
20 kHz to 50 kHz	1 V to 10 V	0.03 % of rdg + 0.23 mV	
50 kHz to 100 kHz	1 V to 10 V	0.09 % of rdg + 0.23 mV	1
100 kHz to 300 kHz	1 V to 10 V	0.35 % of rdg + 1.2 mV	1
300 kHz to 1 MHz	1 V to 10 V	1.2 % of rdg + 1.2 mV	
1 MHz to 2 MHz	1 V to 10 V	1.7 % of rdg + 1.2 mV	



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Equipment to Output AC V	oltage ^{FO}		Keysight 3458A
(At the listed frequencies)			GIDEP
1 Hz to 40 Hz	10 V to 100 V	0.02 % of rdg + 4.6 mV	
40 Hz to 1 kHz	10 V to 100 V	0.02 % of rdg + 2.3 mV	
1 kHz to 20 kHz	10 V to 100 V	0.02 % of rdg + 2.3 mV	
20 kHz to 50 kHz	10 V to 100 V	0.04 % of rdg + 2.3 mV	
50 kHz to 100 kHz	10 V to 100 V	0.14 % of rdg + 2.3 mV	
100 kHz to 300 kHz	10 V to 100 V	0.46 % of rdg + 12 mV	
300 kHz to 1 MHz	10 V to 100 V	1.7 % of rdg + 12 mV	
Equipment to Output AC V (At the listed frequencies)	oltage ^{FO}		
1 Hz to 40 Hz	100 V to 1 000 V	0.05 % of rdg + 46 mV	
40 Hz to 1 kHz	100 V to 1 000 V	0.05 % of rdg + 23 mV	
1 kHz to 20 kHz	100 V to 1 000 V	0.07% of rdg + 23 mV	
20 kHz to 50 kHz	100 V to 1 000 V	0.14 % of rdg + 23 mV	
50 kHz to 100 kHz	100 V to 1 000 V	0.35 % of rdg + 23 mV	
Equipment to Output AC Co (At the listed frequencies)	urrent ^{FO}		
1 Hz to 20 Hz	100 pA to 100 µA	0.46 % of rdg + 35 nA	
20 Hz to 45 Hz	100 pA to 100 µA	0.17 % of rdg + 35 nA	
45 Hz to 100 Hz	100 pA to 100 µA	0.07 % of rdg + 35 nA	
100 Hz to 5 kHz	100 pA to 100 µA	0.07 % of rdg + 35 nA	
Equipment to Output AC C (At the listed frequencies)	urrent ^{FO}		
1 Hz to 20 Hz	100 µA to 1 mA	0.46 % of rdg + 0.23 µA	K.
20 Hz to 45 Hz	100 µA to 1 mA	0.17% of rdg + 0.23μ A	
45 Hz to 100 Hz	100 µA to 1 mA	0.07% of rdg + 0.23μ A]
100 Hz to 5 kHz	100 µA to 1 mA	0.03% of rdg + 0.23μ A	
5 kHz to 20 kHz	100 µA to 1 mA	0.07% of rdg + 0.23μ A	
20 kHz to 50 kHz	100 µA to 1 mA	0.46% of rdg + 0.23μ A	
50 kHz to 100 kHz	100 µA to 1 mA	0.64 % of rdg + 0.23 µA	



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Electrical	-		
MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Equipment to Output AC Cu	urrent ^{FO}		Keysight 3458A
(At the listed frequencies) 1 Hz to 20 Hz	1 mA to 10 mA	0.46 % of rdg + 2.3 μA	GIDEP
20 Hz to 45 Hz	1 mA to 10 mA	0.40% of rdg + 2.3 μ A	
45 Hz to 100 Hz	1 mA to 10 mA	. .	
100 Hz to 5 kHz	1 mA to 10 mA	0.07 % of rdg + 2.3 μA 0.03 % of rdg + 2.3 μA	
5 kHz to 20 kHz	1 mA to 10 mA	. .	
20 kHz to 50 kHz		0.07% of rdg + 2.3 μ A	
	1 mA to 10 mA	$0.46 \% \text{ of } rdg + 2.3 \mu \text{A}$	
50 kHz to 100 kHz	1 mA to 10 mA	0.64% of rdg + 2.3μ A	
Equipment to Output AC Co (At the listed frequencies)	irrent ¹⁰		
1 Hz to 20 Hz	10 mA to 100 mA	0.46 % of rdg + 23 μA	
20 Hz to 45 Hz	10 mA to 100 mA	0.17 % of rdg + 23 μA	
45 Hz to 100 Hz	10 mA to 100 mA	0.07 % of rdg + 23 μA	
100 Hz to 5 kHz	10 mA to 100 mA	0.03 % of rdg + 23 μA	
5 kHz to 20 kHz	10 mA to 100 mA	0.07 % of rdg + 23 μA	
20 kHz to 50 kHz	10 mA to 100 mA	0.46 % of rdg + 46 μ A	
50 kHz to 100 kHz	10 mA to 100 mA	0.64 % of rdg + 0.17 mA	
Equipment to Output AC Co (At the listed frequencies)	urrent ^{FO}		
1 Hz to 20 Hz	100 mA to 1 A	0.46 % of rdg + 0.23 mA	
20 Hz to 45 Hz	100 mA to 1 A	0.18 % of rdg + 0.23 mA	
45 Hz to 100 Hz	100 mA to 1 A	0.09 % of rdg + 0.23 mA	
100 Hz to 5 kHz	100 mA to 1 A	0.12 % of rdg + 0.23 mA	
5 kHz to 20 kHz	100 mA to 1 A	0.35 % of rdg + 0.23 mA	
20 kHz to 50 kHz	100 mA to 1 A	1.2 % of rdg + 0.46 mA	
Equipment to Output AC Current ^{FO} (At the listed frequencies)			Agilent 34401A GIDEP
3 Hz to 5 Hz	1 A to 3 A	1.3 % of rdg + 2.1 mA	
5 Hz to 10 Hz	1 A to 3 A	0.4 % of rdg + 2.1 mA	
10 Hz 5 kHz	1 A to 3 A	0.17 % of rdg + 2.1 mA	
(At the listed frequencies)	Equipment to Output AC Current ^{FO}		
45 Hz to 1 kHz	3 A to 6 A	1.7 % of rdg + 5 mA	
45 Hz to 1 kHz	6 A to 10 A	1.7 % of rdg + 43 mA	



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Electrical			
MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Equipment to Measure	$10 \text{ m}\Omega$ to $100 \text{ m}\Omega$	$60 \ \mu\Omega/\Omega + 0.20 \ m\Omega$	QuadTech 1433-29
Resistance – Resistor	100 m Ω to 1 Ω	$62 \mu\Omega/\Omega + 0.2 \mathrm{m}\Omega$	GIDEP
Based ^{FO}	1 Ω to 10 Ω	44 μΩ/Ω + 7.2 μΩ	
	10 Ω to 100 Ω	35 μΩ/Ω + 7.2 μΩ	
	100 Ω to 1 k Ω	31 μΩ/Ω + 58 μΩ	
	1 kΩ to 10 kΩ	$31 \mu\Omega/\Omega + 0.58 \mathrm{m}\Omega$	
	$10 \text{ k}\Omega$ to $100 \text{ k}\Omega$	$31 \mu\Omega/\Omega + 5.8 \mathrm{m}\Omega$	
	100 kΩ to 1 MΩ	$24 \ \mu\Omega/\Omega + 21 \ m\Omega$	IET Labs HRRS-B-5-100k
	1 MΩ to 10 MΩ	$42 \mu\Omega/\Omega + 61 m\Omega$	GIDEP
	10 MΩ to 100 MΩ	$0.12 \text{ m}\Omega/\Omega + 0.58 \Omega$	
	100 MΩ to 1 GΩ	$0.15 \text{ m}\Omega/\Omega + 5.8 \Omega$	
	1 GΩ to 10 GΩ	$0.65 \text{ m}\Omega/\Omega + 58 \Omega$	

Mass, Force, and Weighing Devices

MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Analytical Balances FO	1 mg to 20 mg	0.003 5 mg	Class ASTM 1 Weight
	20 mg to 500 mg	0.003 8 mg	CM-1009
	500 mg to 2 g	0.006 7 mg	
	2 g to 5 g	0.007 6 mg	
	5 g to 10 g	0.010 4 mg	
	10 g to 20 g	0.015 3 mg	
	20 g to 50 g	0.025 2 mg	
	50 g to 100 g	0.05 mg	
	100 g to 200 g	0.1 mg	
	200 g to 500 g	0.25 mg	
Bench Scales/Balances FO	500 g to 1 kg	0.07 mg	Class ASTM 1 Weight
	1 kg to 2 kg	0.51 mg	CM-1008
	2 kg to 5 kg	1.3 mg	Class ASTM 2 Weight CM-1008
	5 kg to 10 kg	1.3 mg	Class ASTM 1 Weight
	10 kg to 20 kg	5.2 mg	CM-1008
	20 kg to 25 kg	11 mg	
	25 kg to 125 kg	30 mg	Class NIST F Weights CM-1008

This supplement is in conjunction with certificate #L23-302



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MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Pipettes ^{FO}	1 μL to 100 μL	0.29 μL	A&D AD-4212B-PT
	100 µL to 1 000 µL	0.47 μL	CM-1023
	1 000 µL to 10 000 µL	3.8 μL	
Equipment to Measure	0.001 gf to 500 gf	0.001 7 % of rdg + 0.001 8 gf	ASTM Class 1 Weights CM-1015
Force – Tension and	0.5 kgf to 25 kgf	0.001 7 % of rdg + 0.000 033 kgf	
Compression FO	55 lbf to 1 000 lbf	0.003 8 % of reading + 0.13 lbf	Morehouse Precision CM-1015
	1 000 lbf to 25 000 lbf	0.003 0 % of reading + 1.2 lbf	Morehouse Precision CM-1015
Mass Standards ^F	1 mg	0.001 5 mg	Weights, AD4212B-101
	2 mg	0.001 5 mg	Analytical Balance CM-1059
	5 mg	0.001 5 mg	CM-1039
	10 mg	0.001 5 mg	
	20 mg	0.001 6 mg	
	50 mg	0.001 6 mg	
	100 mg	0.001 6 mg	
	200 mg	0.001 7 mg	
	500 mg	0.002 1 mg	
	1 g	0.002 0 mg	
	2 g	0.002 8 mg	
	5 g	0.003 8 mg	
	10 g	0.014 mg	
	20 g	0.015 mg	
	50 g	0.030 mg	
	100 g	0.035 mg	
	200 g	0.13 mg	Weights, MC-1000S Mass
	500 g	0.14 mg	Comparator CM-1059
	1 kg	0.15 mg	
	2 kg	1.5 mg	Weights, MC-10KS Mass
	5 kg	1.9 mg	Comparator CM-1059
	10 kg	2.2 kg	
	20 kg	15 mg	Weights, MC-30KS Mass
	25 kg	18 mg	Comparator CM-1059
	30 kg	18 mg	



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Mass, Force, and Weighing Devices				
MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED	
Burettes ^{FO}	5 mL	7.2 μL	Weights, AD-4212B-PT	
	10 mL	27 μL	CM-1060	
	50 mL	51 μL		
	100 mL	0.15 mL		
Syringes ^{FO}	1 µL to 5 000 µL	0.30 µL	AD-4212B-PT	
	5 mL to 30 mL	4.9 μL	CM-1060	
Diluters/Dispensers ^{FO}	1 mL	5.2 μL	AD-4212B-PT	
	10 mL	28 μL	CM-1060	
	50 mL	0.30 mL		
	100 mL	0.61 mL		
Beakers, Graduated Cylinders, Flasks and Test Tubes ^{FO}	0.1 mL to 500 mL	7.2 μL	Weights, MC-1000S Gravimetric Method CM-1060	
	500 mL to 2 L	6.1 mL	Weights, MC-10KS Gravimetric Method CM-1060	

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Accreditation is granted to the facility to perform the following calibrations:

Mechanical			
MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Pressure Gauge and Transducer ^{FO}	-10 inH2O to 10 inH2O	0.006 1 inH2O	Fluke 700P01 CM-1007
	-1 psi to 1 psi	0.000 45 psi	Fluke 718 1G CM-1007
	Up psi to 30 psi	0.023 psi	Fluke 700P05 CM-1007
	-12 psi to 100 psi	0.032 psi	Fluke 700G06 CM-1007
	100 psi to 500 psi	0.12 psi	Fluke 700G07 CM-1007
	500 psi to 2 000 psi	0.41 psi	Fluke 700G10 CM-1007
	2 000 to 10 000 psi	2.2 psi	Fluke 700G31 CM-1007
Torque Wrench and	20 lbf•in to 200 lbf•in	0.12 % of rdg	AKO TSD011/020
Screwdriver ^F	200 lbf•in to 800 lbf•ft	0.2 % of rdg	AKO TSD821 CM-1001
Durometer – Indentor Length ^{FO} Type A, B, C, D, DO, O, OO	Up to 0.1 in	0.004 6 in	Gage Blocks CM-1037
Durometer – Spring Force	Up to 5 kgf	1.3 gf	Morehouse Precision CM-1037
Type A, B, C, D, DO, O, OO			
Gas Flow Meter ^{FO}	0.05 SCCM to SCCM	0.25 % of rdg + 0.12 SCCM	MC-500SCCM-D CM-1031
	0.5 SLPM to 500 SLPM	0.52 % of rdg + 0.17 SLPM	MCR-500SLPM-D CM-1031

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Accreditation is granted to the facility to perform the following calibrations:

Thermodynamic	· · ·		
MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Temperature Measurement Devices ^{FO}	-196 ° C to 350 ° C	0.02 ° C	GE M2801/IRTD-400 Hart Scientific 7320 Fluke 9103 Fluke 9140 Liquid Nitrogen Cylinder CM-1003
Temperature Sources FO	-196 ° C to 420 ° C	0.016 ° C	GE M2801/IRTD-400 CM-1002
Infrared Temperature Measurement Devices ^{FO}	50 °C to 500 °C	0.37 °C	Fluke 9132 CM-1042
Humidity Measurement	5 % RH to 30 % RH	0.53 % RH	Vaisala HMP75 Folyon H300 CM-1004
Devices FO	> 30 % RH to 45 % RH	0.62 % RH	
	> 45 % RH to 60 % RH	0.72 % RH	CIVI-1004
	> 60 % RH to 80 % RH	0.82 % RH	-
	> 80 % RH to 95 % RH	0.92 % RH	-
Humidity Chambers FO	Up to 30 % RH	0.53 % RH	Vaisala HMP75 CM-1004
	> 30 % RH to 45 % RH	0.62 % RH	
	> 45 % RH to 60 % RH	0.72 % RH	
	> 60 % RH to 80 % RH	0.82 % RH	
	> 80 % RH to 95 % RH	0.92 % RH	

Time and Frequency

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MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED	CALIBRATION EQUIPMENT AND REFERENCE
		AS AN UNCERTAINTY (±)	STANDARDS USED
Stopwatch, Timers FO	Up to 24 h	511 ms	Direct Comparison Method – NIST Audio
			Time Signal
			CM-1014
Time Intervals FO	Up to 24 h	761 ms	Direct Comparison
			Method – Stopwatch
			CM-1014
Equipment to Output	1 Hz to 40 Hz	0.58 mHz/Hz + 50 μHz	Keysight 3458A
Frequency FO	40 Hz to 1 MHz	0.12 mHz/Hz + 50 µHz	GIDEP
	1 MHz to 100 MHz	0.12 mHz/Hz + 5 Hz	



UMT Calibration Laboratory

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- 1. The CMC (Calibration and Measurement Capability) stated for calibrations included on this scope of accreditation represents the smallest measurement uncertainty attainable by the laboratory when performing a more or less routine calibration of a nearly ideal device under nearly ideal conditions. It is typically expressed at a confidence level of 95 % using a coverage factor k (usually equal to 2). The actual measurement uncertainty associated with a specific calibration performed by the laboratory will typically be larger than the CMC for the same calibration since capability and performance of the device being calibrated and the conditions related to the calibration may reasonably be expected to deviate from ideal to some degree.
- 2. The laboratories range of calibration capability for all disciplines for which they are accredited is the interval from the smallest calibrated standard to the largest calibrated standard used in performing the calibration. The low end of this range must be an attainable value for which the laboratory has or has access to the standard referenced. Verification of an indicated value of zero in the absence of a standard is common practice in the procedure for many calibrations but by its definition it does not constitute calibration of zero capacity.
- 3. The presence of a superscript FO means that the laboratory performs calibration of the indicated parameter both at its fixed location and onsite at customer locations. Example: Outside Micrometer^{FO} would mean that the laboratory performs this calibration at its fixed location and onsite at customer locations.
- 4. Measurement uncertainties obtained for calibrations performed at customer sites can be expected to be larger than the measurement uncertainties obtained at the laboratories fixed location for similar calibrations. This is due to the effects of transportation of the standards and equipment and upon environmental conditions at the customer site which are typically not controlled as closely as at the laboratories fixed location.
- 5. The term L represents length in inches or millimeters as appropriate to the uncertainty statement.
- 6. The term R represents radius in inches or millimeters as appropriate to the uncertainty statement.
- 7. The term T represents temperature in °C or °F as appropriate to the uncertainty statement.